Notice of References Cited Application/Control No. 10/561,958 Applicant(s)/Patent Under Reexamination KWON, YONG-DUK Examiner David M. Brunsman Art Unit Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,153,037 A	10-1992	Altieri, Paul A.	428/35.6
*	В	US-2005/0029703 A1	02-2005	Franke et al.	264/151
*	С	US-2003/0047110 A1	03-2003	Poovarodom et al.	106/124.4
*	D	US-6,878,199 B2	04-2005	Bowden et al.	106/162.5
*	E	US-6,805,823 B2	10-2004	Franke et al.	264/151
*	F	US-6,176,915 B1	01-2001	Franke et al.	106/125.1
*	G	US-5,976,235 A	11-1999	Andersen et al.	106/162.51
*	Н	US-5,360,586 A	11-1994	Wyatt et al.	264/54
*	1	US-5,317,037 A	05-1994	Golden et al.	523/128
*	J	US-5,205,863 A	04-1993	Elion, Glenn R.	106/126.3
*	К	US-5,160,368 A	11-1992	Begovich, Juan A.	106/126.2
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N ?	EP001120042A2	08-2001	EP	Yeo	
	0					
	Р				·	
	α					
	R					
	S					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	υ .	
	v .	
	w	
	x	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.